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WeEn Semiconductors



**Product data sheet** 

### 1. General description

Planar passivated high commutation three quadrant triac in a SOT78 (TO-220AB) plastic package. This "series E" triac balances the requirements of commutation performance and gate sensitivity and is intended for interfacing with low power drivers including microcontrollers.

#### 2. Features and benefits

- 3Q technology for improved noise immunity
- Direct interfacing with low power drivers and microcontrollers
- Good immunity to false turn-on by dV/dt
- High commutation capability with sensitive gate
- High voltage capability
- Planar passivated for voltage ruggedness and reliability
- Sensitive gate for easy logic level triggering
- · Triggering in three quadrants only

# 3. Applications

- Electronic thermostats (heating and cooling)
- Motor controls e.g. washing machines and vacuum cleaners
- Refrigeration and air-conditioner compressor controls

#### 4. Quick reference data

Table 1. Quick reference data

| Symbol              | Parameter                                | Conditions  |  | Min | Тур | Max | Unit |
|---------------------|--|---|--|-----|-----|-----|------|
| $V_{DRM}$           | repetitive peak off-<br>state voltage    |   |  | -   | -   | 600 | V    |
| I <sub>TSM</sub>    | non-repetitive peak on-<br>state current | full sine wave; $T_{j(init)} = 25 \text{ °C}$ ;<br>$t_p = 20 \text{ ms}$ ; Fig. 4; Fig. 5 |  | -   | -   | 85  | Α    |
| T <sub>j</sub>      | junction temperature                     |   |  | -   | -   | 125 | °C   |
| I <sub>T(RMS)</sub> | RMS on-state current                     | full sine wave; $T_{mb} \le 106$ °C; Fig. 1;<br>Fig. 2; Fig. 3                            |  | -   | -   | 10  | Α    |
| Static characte     | Static characteristics                   |   |  |     |     |     |      |
| I <sub>GT</sub>     | gate trigger current                     | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$<br>$T_j = 25 \text{ °C}; Fig. 7$       |  | 0.5 | -   | 10  | mA   |





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| Symbol                | Parameter                             | Conditions   | Min | Тур | Max | Unit |
|-----------------------|---------------------------------------|--|-----|-----|-----|------|
|                       |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G-;}$<br>$T_j = 25 \text{ °C; } \frac{\text{Fig. 7}}{}$ | 0.5 | -   | 10  | mA   |
|                       |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } \frac{\text{Fig. 7}}{}$             | 0.5 | -   | 10  | mA   |
| Dynamic char          | acteristics                           |  |     |     |     | •    |
| dV <sub>D</sub> /dt   | rate of rise of off-state voltage     | $V_{DM}$ = 402 V; $T_j$ = 125 °C; $(V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit      | 50  | -   | -   | V/µs |
| dl <sub>com</sub> /dt | rate of change of commutating current | $V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 10 A; $dV_{com}/dt$ = 1 V/ $\mu$ s; gate open circuit            | 6   | -   | -   | A/ms |

# 5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description                    | Simplified outline | Graphic symbol |
|-----|--------|--------------------------------|--------------------|----------------|
| 1   | T1     | main terminal 1                | mb                 | T2—T1          |
| 2   | T2     | main terminal 2                |                    | Sym051         |
| 3   | G      | gate                           |                    | ,              |
| mb  | T2     | mounting base; main terminal 2 |                    |                |
|     |        |                                | TO-220AB (SOT78)   |                |

# 6. Ordering information

Table 3. Ordering information

| Type number | Package  |  |         |
|-------------|----------|--|---------|
|             | Name     | Description  | Version |
| BTA310-600E | TO-220AB | plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB | SOT78   |

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# 7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol              | Parameter                            | Conditions   | Min | Max  | Unit             |
|---------------------|--------------------------------------|--|-----|------|------------------|
| $V_{DRM}$           | repetitive peak off-state voltage    |  | -   | 600  | V                |
| I <sub>T(RMS)</sub> | RMS on-state current                 | full sine wave; $T_{mb} \le 106 ^{\circ}\text{C}$ ; Fig. 2; Fig. 3                       | -   | 10   | Α                |
| I <sub>TSM</sub>    | non-repetitive peak on-state current | full sine wave; $T_{j(init)} = 25 ^{\circ}C$ ;<br>$t_p = 20  \text{ms}$ ; Fig. 4; Fig. 5 | -   | 85   | A                |
|                     |                                      | full sine wave; $T_{j(init)} = 25 ^{\circ}C$ ;<br>$t_p = 16.7  \text{ms}$                | -   | 93   | A                |
| I <sup>2</sup> t    | I <sup>2</sup> t for fusing          | t <sub>p</sub> = 10 ms; SIN  | -   | 36.1 | A <sup>2</sup> s |
| dl <sub>T</sub> /dt | rate of rise of on-state current     | $I_T = 20 \text{ A}; I_G = 0.2 \text{ A}; dI_G/dt = 0.2 \text{ A/}\mu\text{s}$           | -   | 100  | A/µs             |
| I <sub>GM</sub>     | peak gate current                    |  | -   | 2    | Α                |
| $P_{GM}$            | peak gate power                      |  | -   | 5    | W                |
| P <sub>G(AV)</sub>  | average gate power                   | over any 20 ms period  | -   | 0.5  | W                |
| T <sub>stg</sub>    | storage temperature                  |  | -40 | 150  | °C               |
| Tj                  | junction temperature                 |  | -   | 125  | °C               |

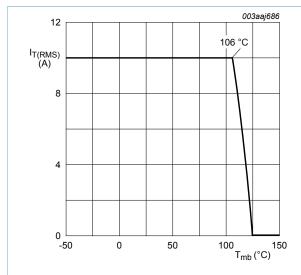
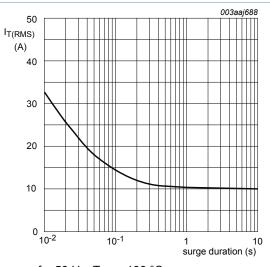


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



 $f = 50 \text{ Hz}; T_{mb} = 106 ^{\circ}\text{C}$ 

Fig. 2. RMS on-state current as a function of surge duration; maximum values

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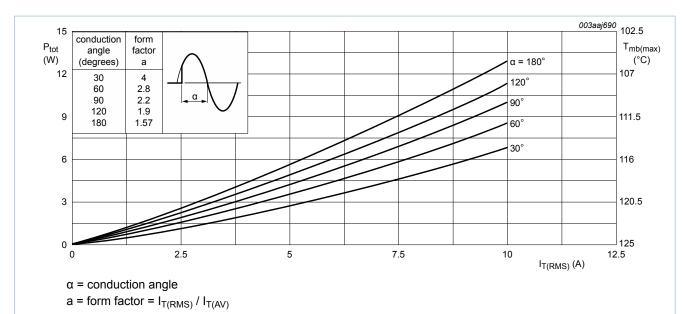


Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

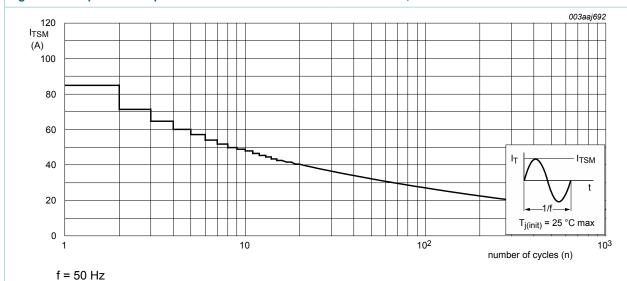
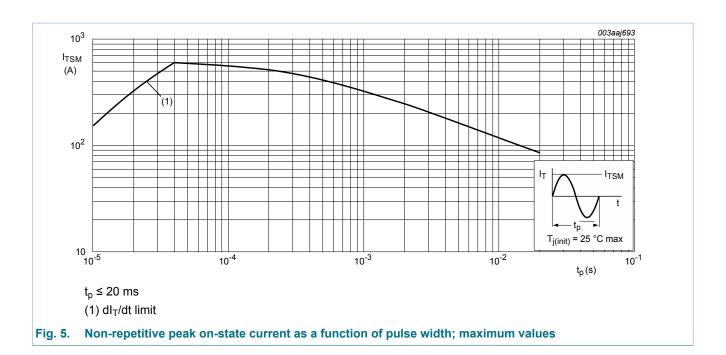


Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

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### 8. Thermal characteristics

Table 5. Thermal characteristics

| Symbol  | Parameter   | Conditions         | Min | Тур | Max | Unit |
|---|---|--------------------|-----|-----|-----|------|
| R <sub>th(j-mb)</sub> thermal resistance from junction to mounting base |   | full cycle; Fig. 6 | -   | -   | 1.5 | K/W  |
|   |   | half cycle; Fig. 6 | -   | -   | 2   | K/W  |
| R <sub>th(j-a)</sub>  | thermal resistance<br>from junction to<br>ambient | in free air        | -   | 60  | -   | K/W  |

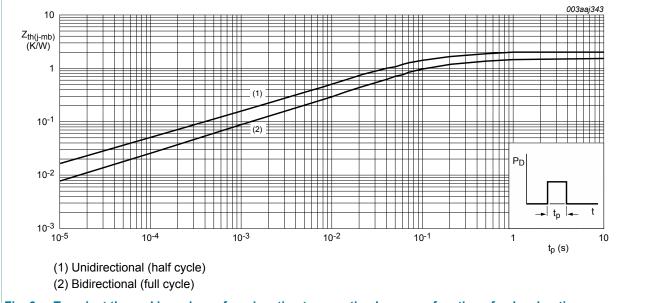


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

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# 9. Characteristics

#### Table 6. Characteristics

| Symbol                               | Parameter                             | Conditions  | Min  | Тур  | Max | Unit |
|--------------------------------------|---------------------------------------|---|------|------|-----|------|
| Static cha                           | racteristics                          |   |      |      |     |      |
| I <sub>GT</sub> gate trigger current | gate trigger current                  | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ G+;$<br>$T_j = 25 \text{ °C; } Fig. 7$  | 0.5  | -    | 10  | mA   |
|                                      |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + \text{G-;}$<br>$T_j = 25 \text{ °C; } Fig. 7$                                | 0.5  | -    | 10  | mA   |
|                                      |                                       | $V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2-\text{ G-;}$<br>$T_j = 25 \text{ °C; } Fig. 7$                                 | 0.5  | -    | 10  | mA   |
| IL                                   | I <sub>L</sub> latching current       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G+;$<br>$T_j = 25 \text{ °C}; Fig. 8$   | -    | -    | 25  | mA   |
|                                      |                                       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G-;$<br>$T_j = 25 \text{ °C}; Fig. 8$   | -    | -    | 30  | mA   |
|                                      |                                       | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G-};$<br>$T_j = 25 ^{\circ}\text{C}; \text{ Fig. 8}$                     | -    | -    | 25  | mA   |
| I <sub>H</sub>                       | holding current                       | V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>  | -    | -    | 15  | mA   |
| V <sub>T</sub>                       | on-state voltage                      | I <sub>T</sub> = 12 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>   | -    | 1.25 | 1.5 | V    |
| V <sub>GT</sub> gate trigger vol     | gate trigger voltage                  | V <sub>D</sub> = 12 V; I <sub>T</sub> = 0.1 A; T <sub>j</sub> = 25 °C;<br>Fig. 11   | -    | 0.7  | 1   | V    |
|                                      |                                       | V <sub>D</sub> = 400 V; I <sub>T</sub> = 0.1 A; T <sub>j</sub> = 125 °C;<br>Fig. 11   | 0.25 | 0.4  | -   | V    |
| I <sub>D</sub>                       | off-state current                     | V <sub>D</sub> = 600 V; T <sub>j</sub> = 125 °C   | -    | 0.1  | 0.5 | mA   |
| Dynamic c                            | haracteristics                        |   | ,    |      |     |      |
| dV <sub>D</sub> /dt                  | rate of rise of off-state voltage     | $V_{DM}$ = 402 V; $T_j$ = 125 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit                    | 50   | -    | -   | V/µs |
| 00111                                | rate of change of commutating current | $V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 10 A; $dV_{com}/dt$ = 20 V/ $\mu$ s; (snubberless condition); gate open circuit | 2    | -    | -   | A/ms |
|                                      |                                       | $V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 10 A; $dV_{com}/dt$ = 10 V/ $\mu$ s; gate open circuit                          | 3    | -    | -   | A/ms |
|                                      |                                       | $V_D$ = 400 V; $T_j$ = 125 °C; $I_{T(RMS)}$ = 10 A; $dV_{com}/dt$ = 1 V/µs; gate open circuit                                 | 6    | -    | -   | A/ms |

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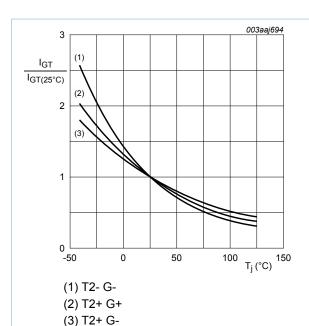


Fig. 7. Normalized gate trigger current as a function of junction temperature

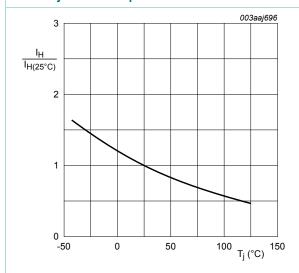


Fig. 9. Normalized holding current as a function of junction temperature

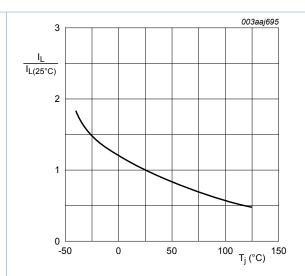
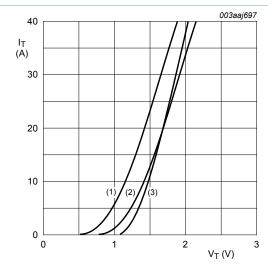


Fig. 8. Normalized latching current as a function of junction temperature



 $V_0 = 1.103 \text{ V}; R_s = 0.030 \Omega$ 

(1) T<sub>j</sub> = 125 °C; typical values

(2) T<sub>i</sub> = 125 °C; maximum values

(3) T<sub>i</sub> = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

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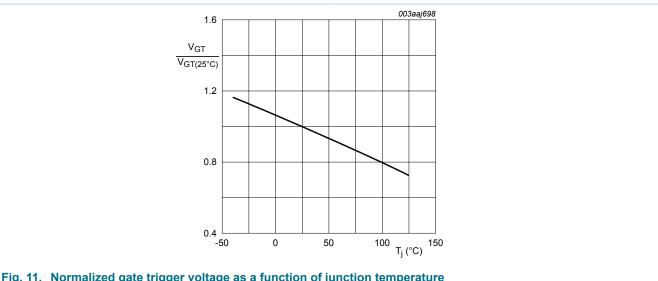
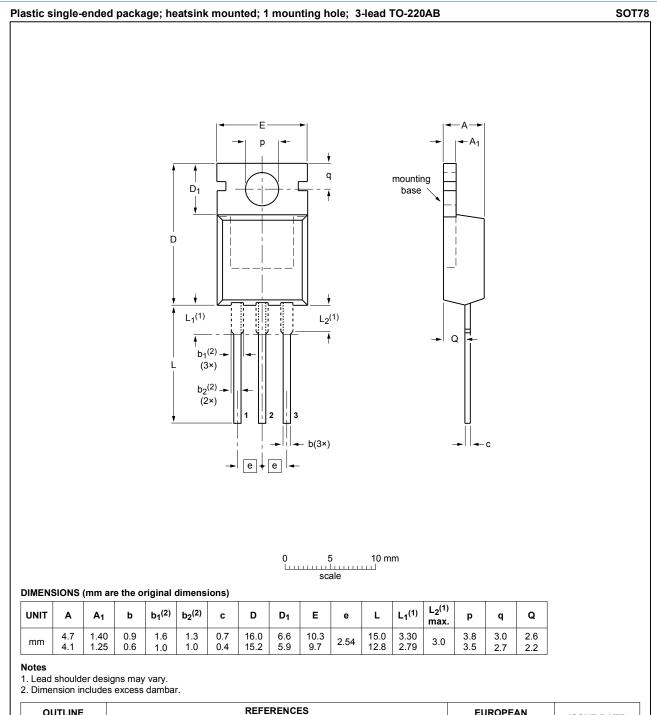


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

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# 10. Package outline



| OUTLINE |     | REFER           | ENCES | EUROPEAN   | ISSUE DATE                      |  |
|---------|-----|-----------------|-------|------------|---------------------------------|--|
| VERSION | IEC | JEDEC           | JEITA | PROJECTION | 1330E DATE                      |  |
| SOT78   |     | 3-lead TO-220AB | SC-46 |            | <del>08-04-23</del><br>08-06-13 |  |

Fig. 12. Package outline TO-220AB (SOT78)

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|--------------------------------------|--------------------|---|
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